

First Results from F-CSA104 »Gullinbursti«

C.Bauer B.Schwingenheuer N.Smole U.Trunk

Max-Planck-Institut für Kernphysik

W. Fallot-Burghardt

fbe ASIC Design and Consulting

Outline

- Overview
 - Requirements
 - Schematics
 - Layout
- Tests and Results
 - Setup and Infrastructure
 - I²C
 - Power Consumption and Ref. CS
 - Pulse Shape
 - Linearity
 - Noise
 - Long Cables
- Summary & Conclusions

Requirements

- Very low Noise ($ENC=220e^-$ @ $C_{det} = 30pF$, $T=27^\circ C$, $t_{peak} = 20\mu s$)
- Temperature Range $-200^\circ C \dots +50^\circ C$
- Fast differential Outputs ($t_{rise} < 30ns$)
- Gain $5.84mV/fC$, $316mV/MeV$ (Ge), $258mV/MeV$ (Si)
- Input Signal Range $\pm 600fC$, $\pm 11MeV$ (Ge), $\pm 13MeV$ (Si)
- 14bit Linearity for Spectroscopy Applications
- Adjustable Preamplifier Time Constant $1\mu s \dots 1.5ms$
- Optional Connection of external p-Channel FET
- Optimised for Detectors of $30pF$ ($0 \dots 100pF$)
- All Stages DC coupled, Offset Suppression
- I²C-Interface for Parameter Adjustment

Layout

- F-CSA104 Chip Layout

Reference Channel 1	Diff. Output Driver
Channel 1	

Reference Channel 2	Diff. Output Driver
Channel 2	

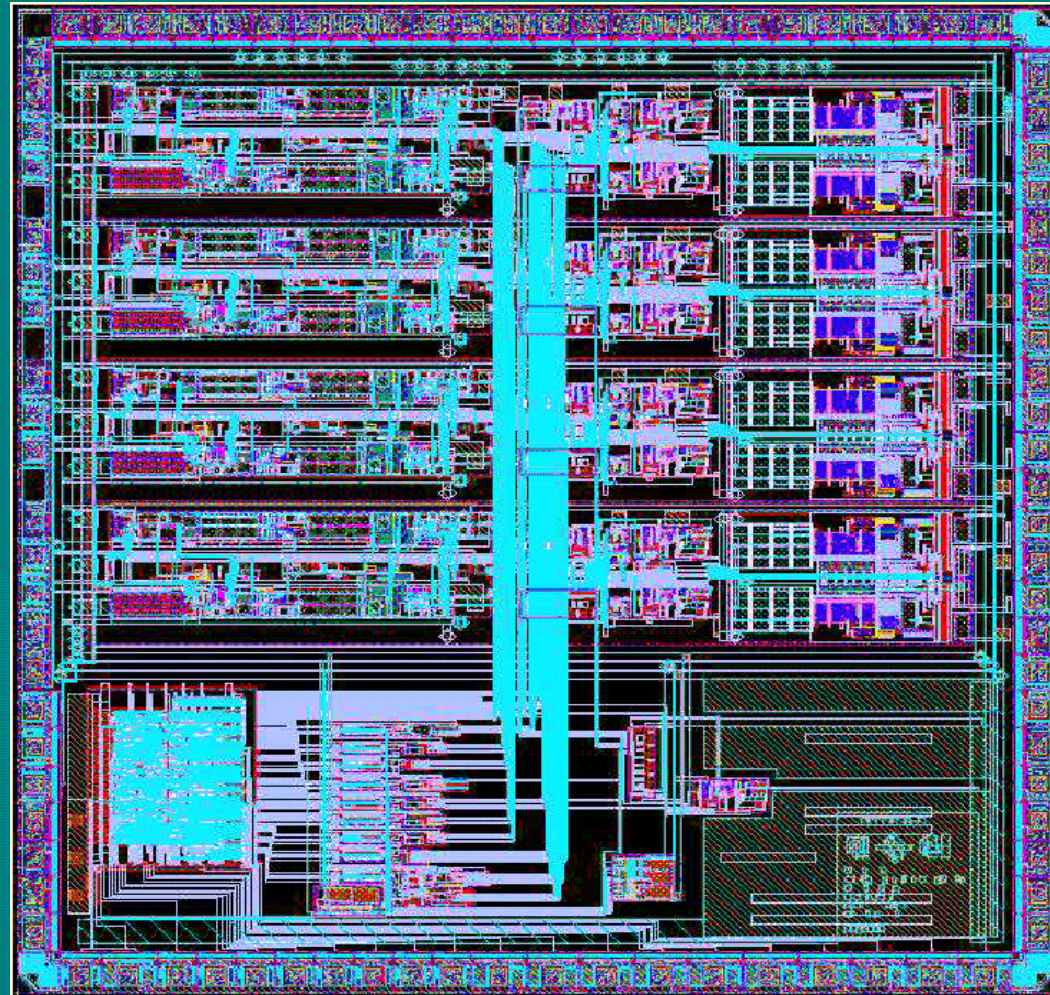
Reference Channel 3	Diff. Output Driver
Channel 3	

Reference Channel 4	Diff. Output Driver
Channel 4	

I²C-
Inter-
face

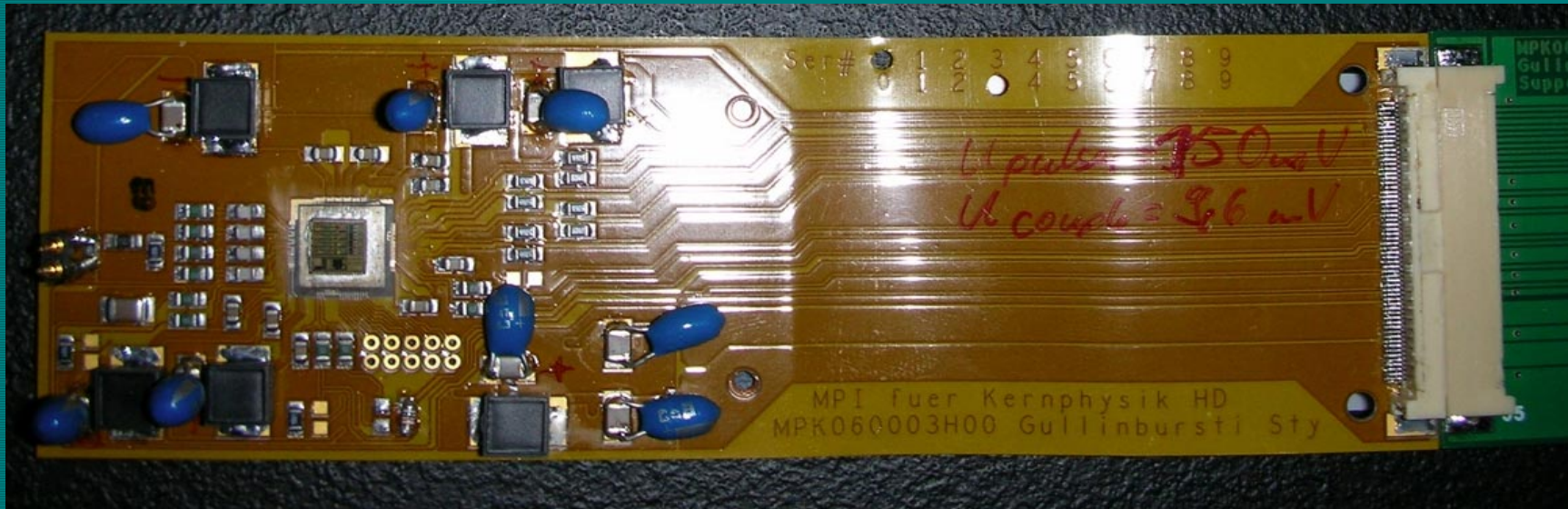
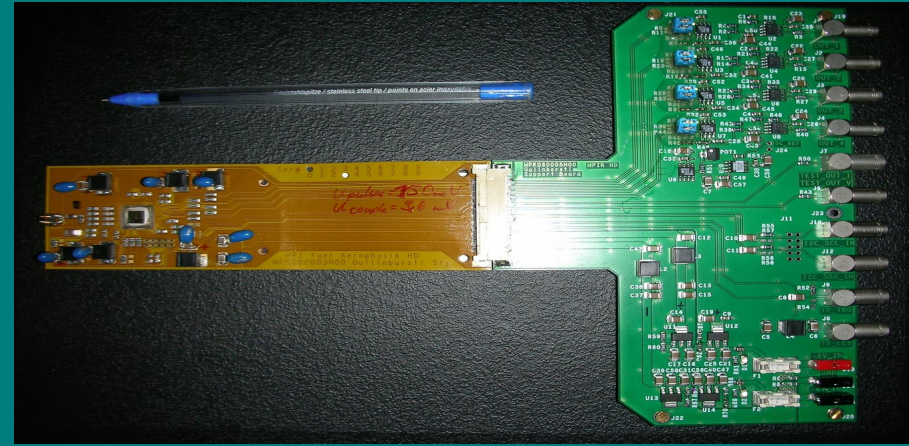
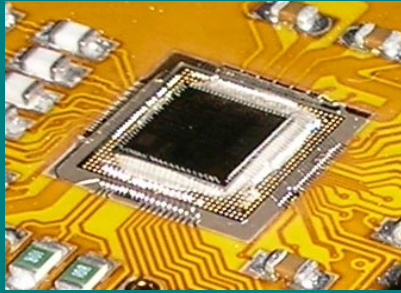
Bias-
Gen.

Test-
Mux



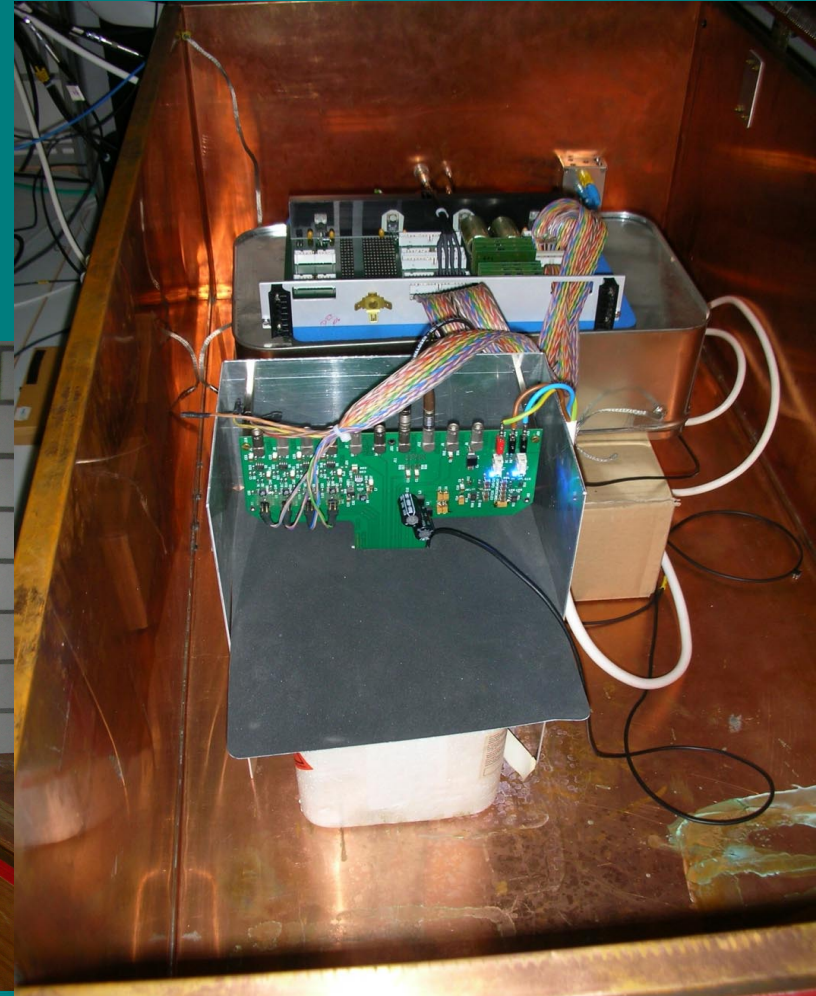
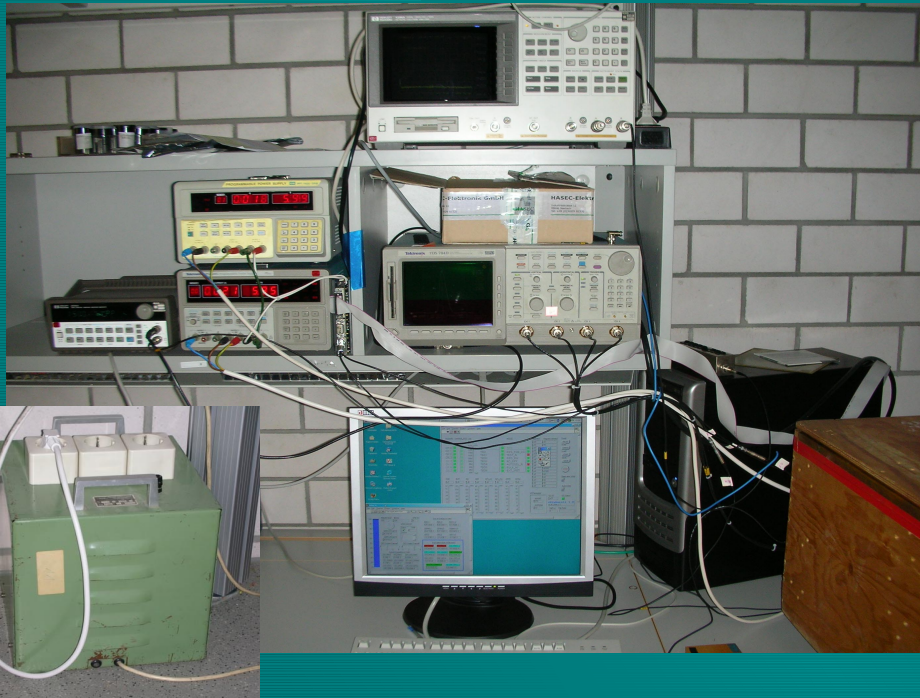
Test Setup

- F-CSA104 Board
- Differential Receiver
- CR-(RC)⁴-Shaper



Test Setup

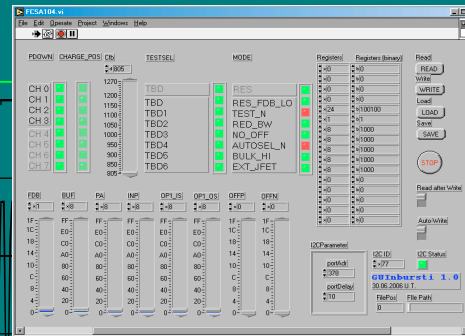
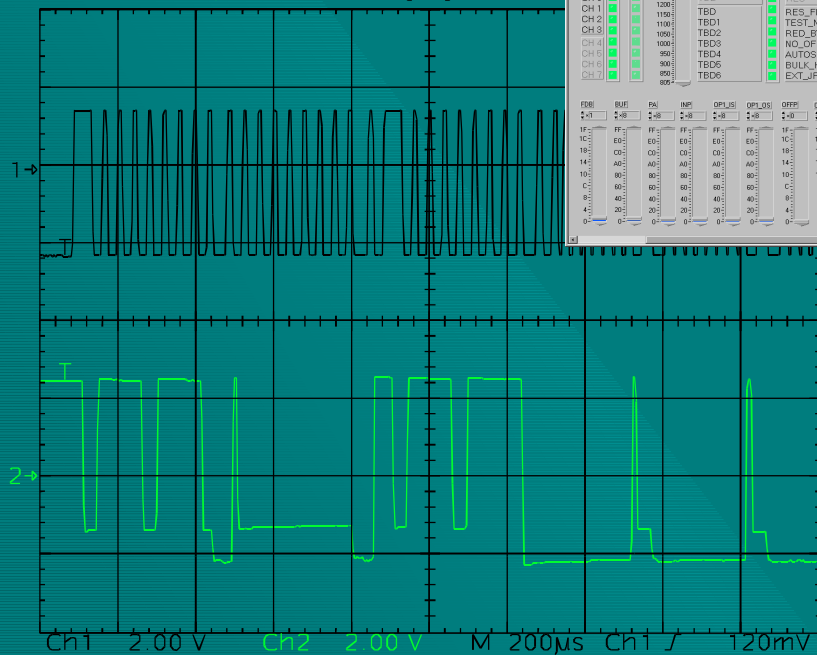
- Isolation Transformer
- Shielding Box
- Spectrum Analyser
- TDS784D Scope
- PC



I²C-Interface

- Requires Levelshifter (0-5V -> ±2.5V)
- Register Map »off-by-one«
- Works!

Tek Run: 250KS/s Hi Res Trig?



Register Name	Register Address	Default Value
	0x00	0x00
PDOWN	0x00	0x01
CFB	0x01	0x02
TESTSEL	0x02	0x03
MODE	0x03	0x04
FDB	0x04	0x05
BUF	0x05	0x06
PA	0x06	0x07
INP	0x07	0x08
OP1_IS	0x08	0x09
OP1_OS	0x09	0x0A
RESERVED	0x0A	0x0B
RESERVED	0x0B	0x0C
OFFP	0x0C	0x0D
OFFN	0x0D	0x0E
CHARGE PO	0x0E	0x1F
	0x1F	0x10
	0x10	0x11
...
	0xFE	0xFF
	0xFF	

27 Jun 2006
12:11:11

Power Consumption

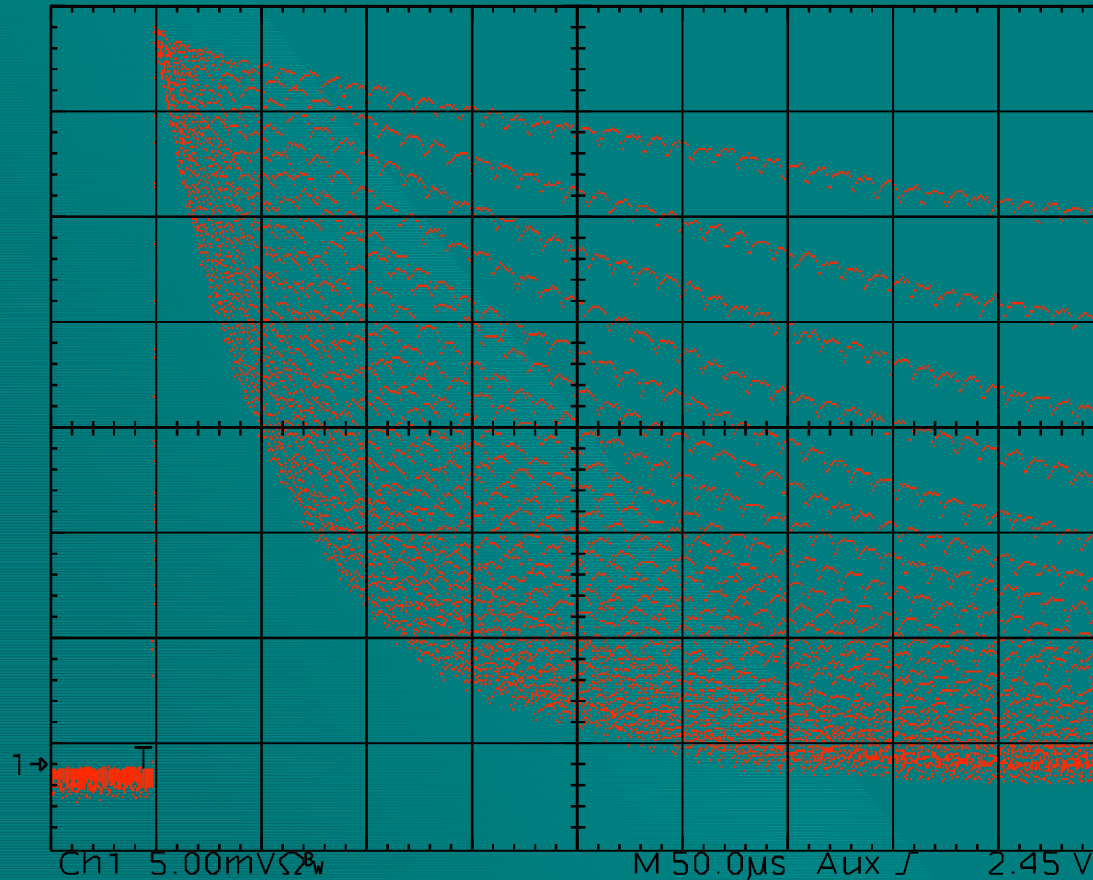
- Higher than Simulation (w/o Pads and I²C)
- Channel Power very uniform
 - Almost no Difference between 300K and 77K
 - Due to Ref. Current Source (Sim: 28ppm/°C)

	Measured				sim.
	77K		300K		
	Vdd	Vss	Vdd	Vss	
4 channels	65mA	75mA	73mA	79mA	60.0mA
3 channels	55mA	64mA	62mA	67mA	50.5mA
2 channels	45mA	53mA	51mA	55mA	41.0mA
1 channel	35mA	42mA	43mA	45mA	31.5mA
0 channels	25mA	30mA	33mA	35mA	22.0mA

Pulse Shape

● Pulse Shape for different R_{fb} Values

Tek Stop: 1.00MS/s 31 Acqs



Cp	33 pF	100pF
trise (77 K)	10 ns	12 ns
trise (300K)	18 ns	24 ns
trise (sim., 300K)a	22 ns(b)	28 ns(c)

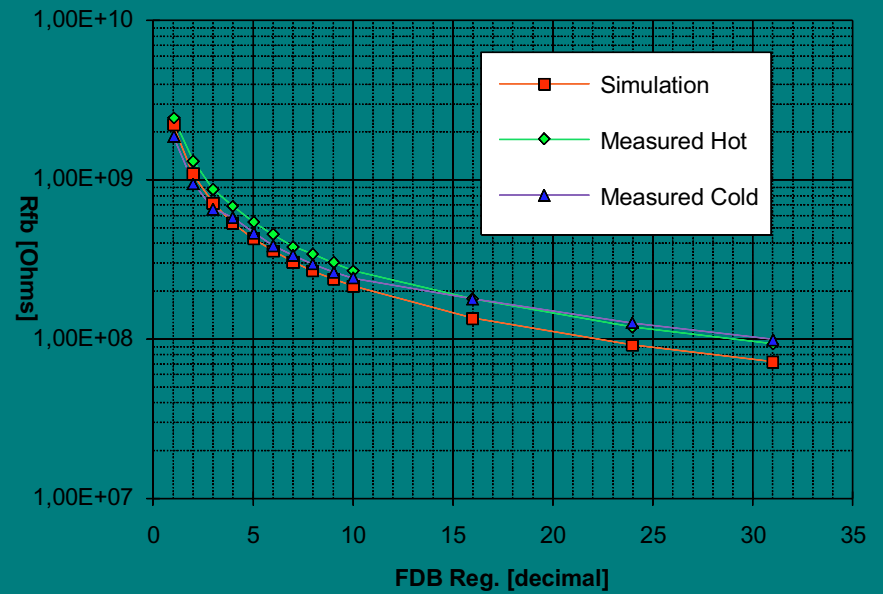
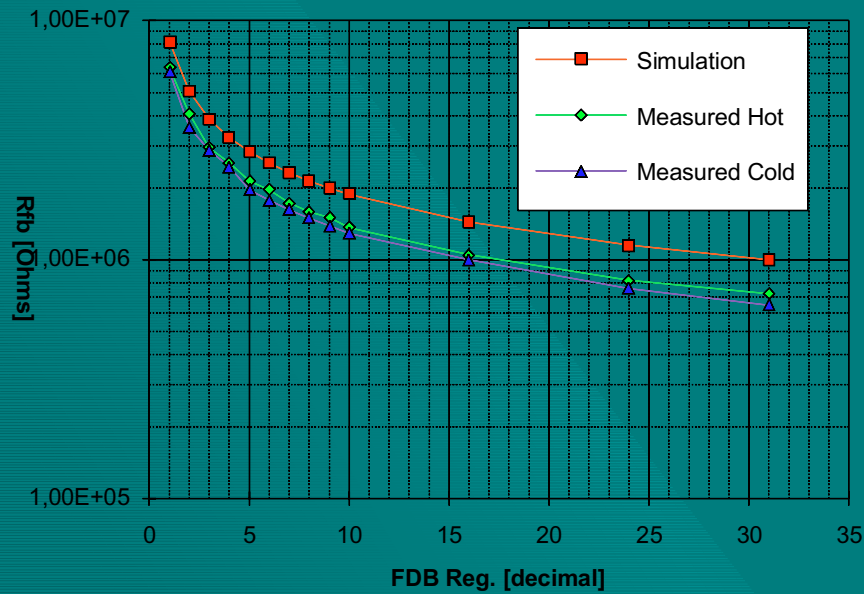
- (a) with Cp = 0
- (b) Qin = 40fC
- (c) Q = 541 fC (1MeV (Ge))

Ch1 5.00mV/div M 50.0µs Aux J 2.45 V 3 Jul 2006

16:41:05

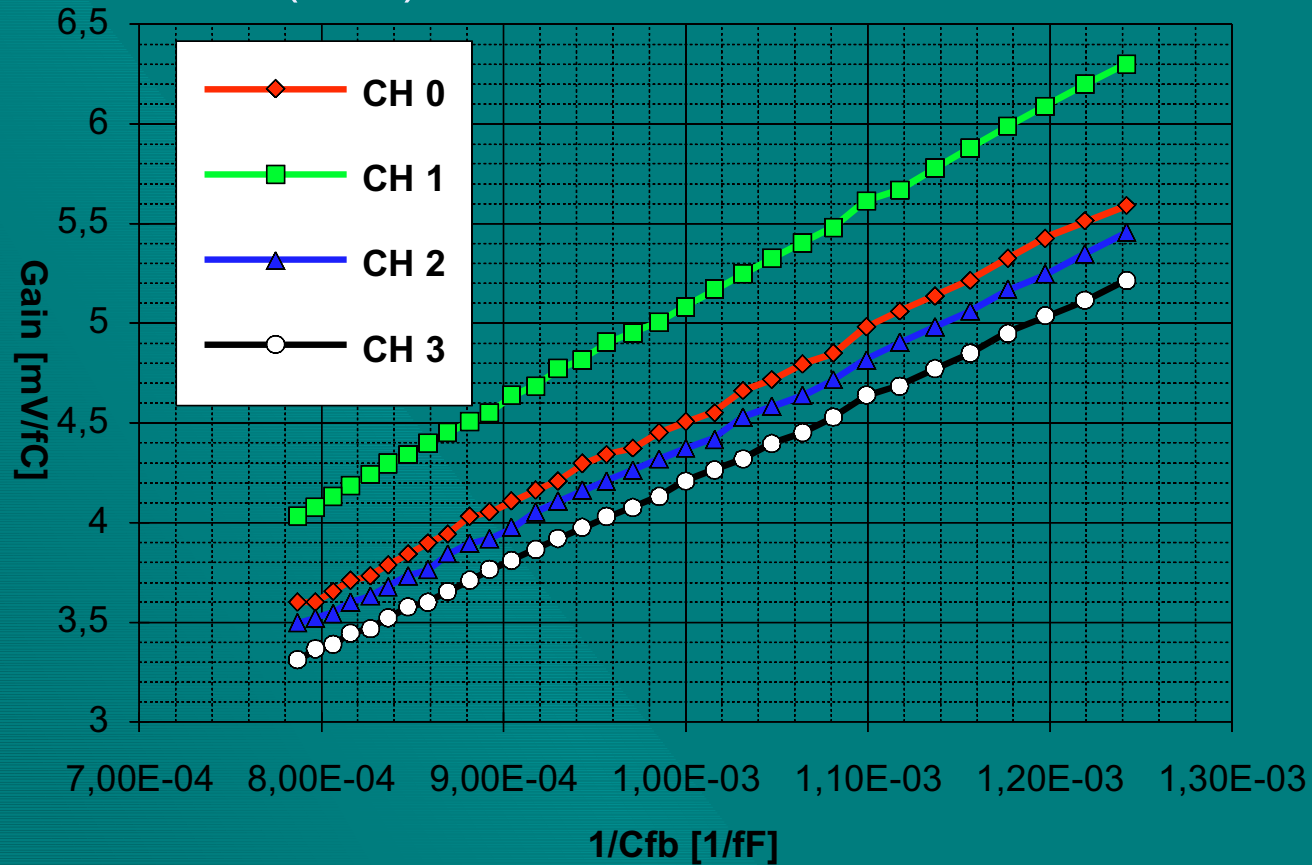
Pulse Shape

- R_{fb} Values from measured Decay Times



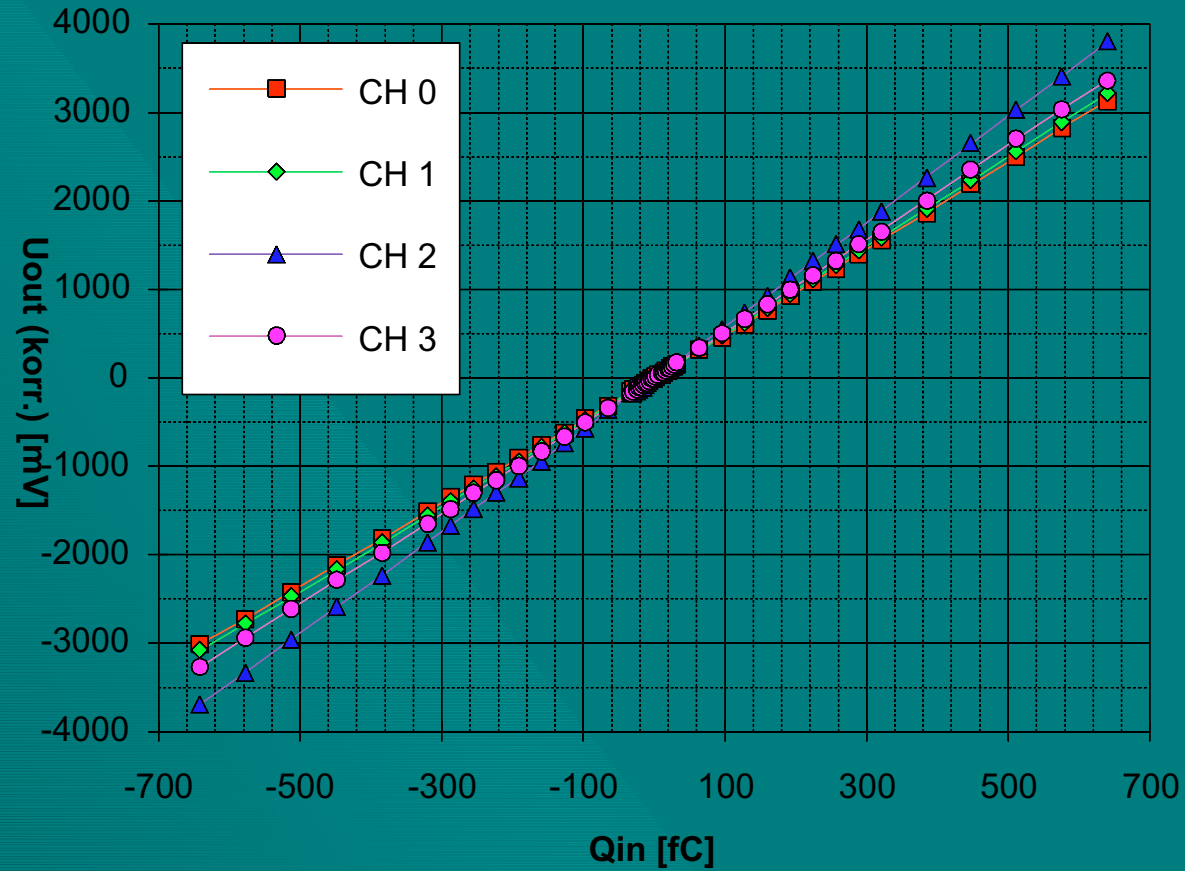
Gain

- Less than expected:
 - 4.7 mV/fC (meas.)
 - 5.84mV/fC (sim.)



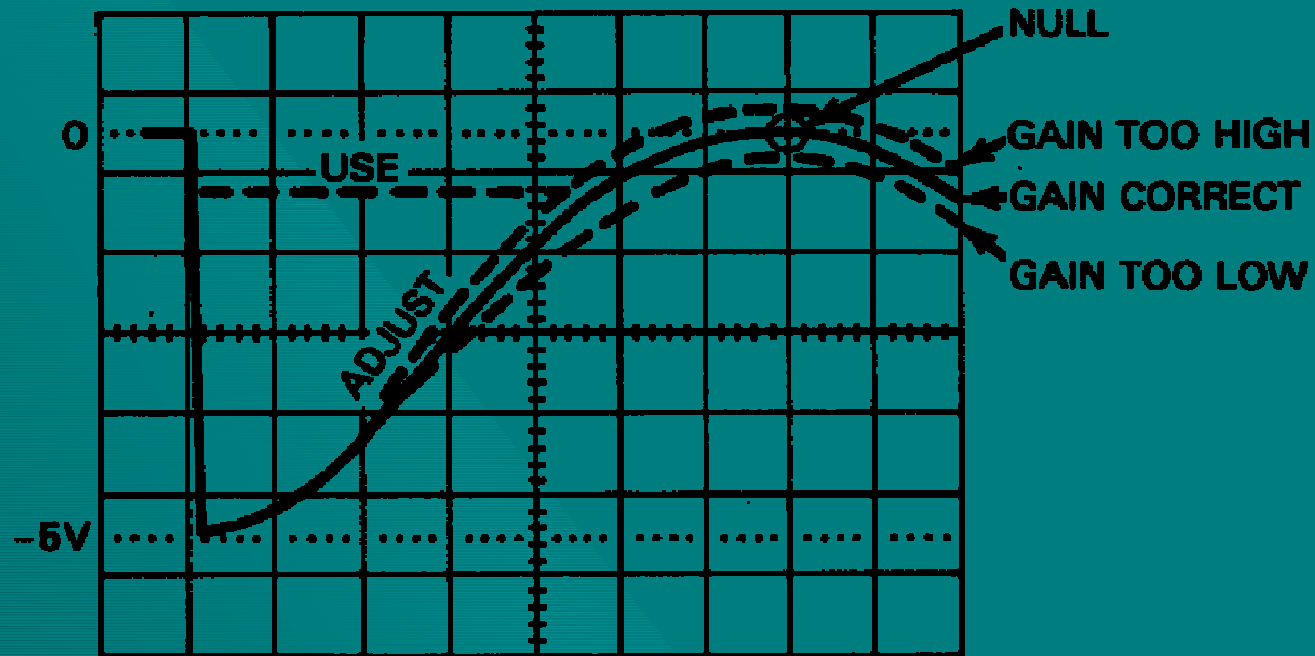
Linearity

- 14bit Equivalent



Linearity

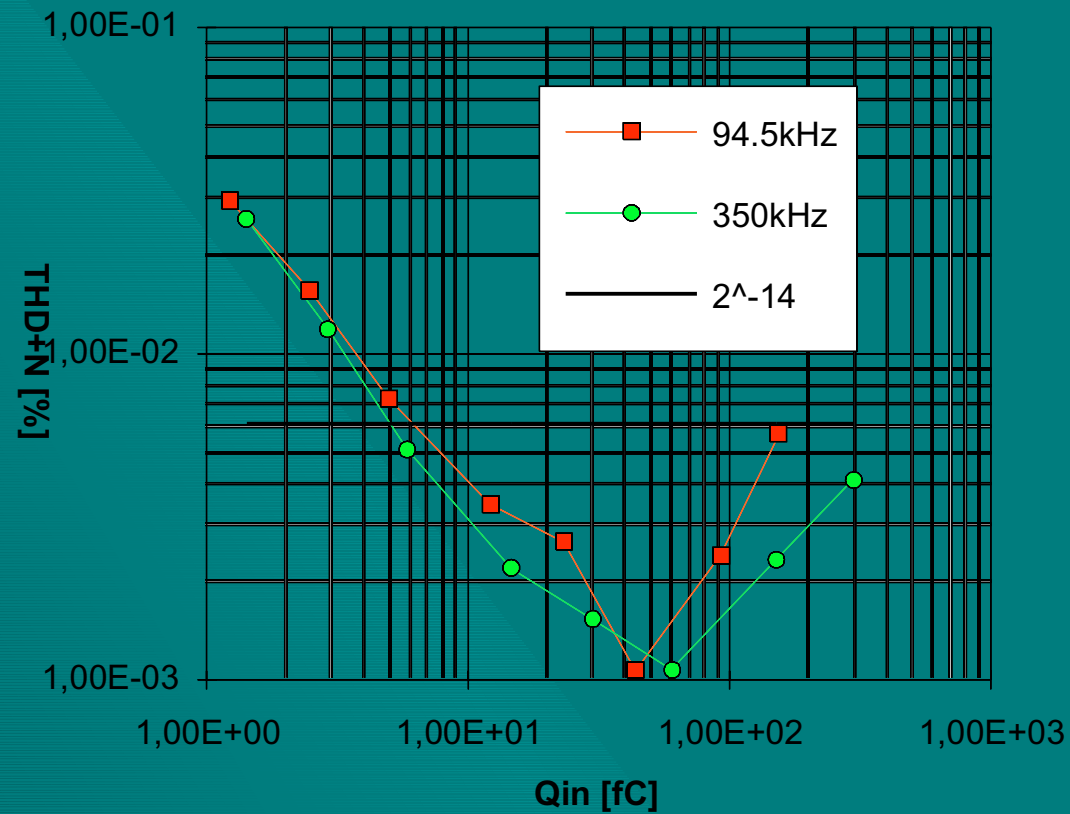
- IEEE Std. 301-1988
 - $\Delta U \approx 150 \mu V$
 - Requirements for Error Amp ($G=100 @ BW > 10 \text{MHz}$)



Linearity

- THD+N Method
 - Only upper Limit
 - Shift in Operating Point
 - Frequency dependent

$$NL \leq THD + N = \sum_{i=2}^{\infty} \frac{k_i}{k_1}$$



Noise

- Measurement Setup:
- CR-(RC)⁴-Shaper $t_{\text{peak}} = 20\mu\text{s}$, TDS784D Scope & LabVIEW
- 100Acq \times 5k Samples @ 2.5Ms/s = 250Hz...1.25MHz
- TDS built-in RMS and MEAN Functions
- Struck 100MHz/14bit VME FADC
- Software for Shaping and Analysis
- Comparable Results
- Huge Common Mode

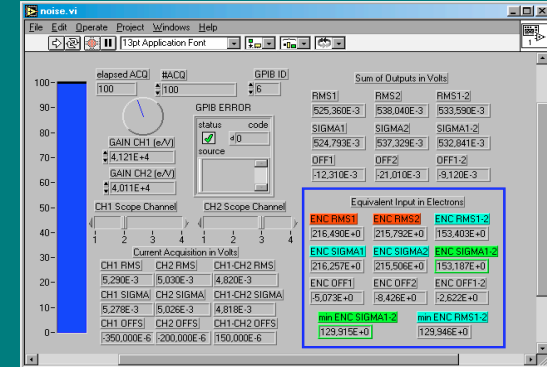
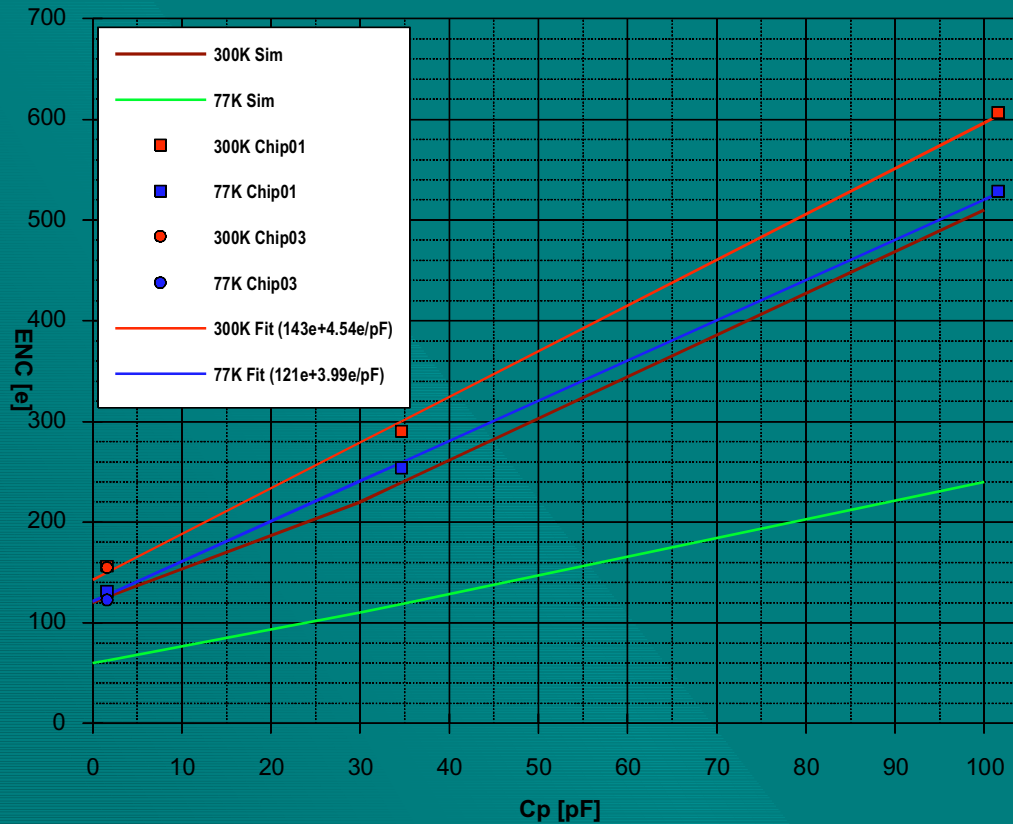
	300K	77K
1.5pF	218e	193e
34.5pF	741e	521e
101.5pF	1900e	1212e

$$\text{ENC} = 194e^- + 16.33e^-/\text{pF} @ 300\text{K}$$

$$\text{ENC} = 177e^- + 10.52e^-/\text{pF} @ 77\text{K}$$

Noise

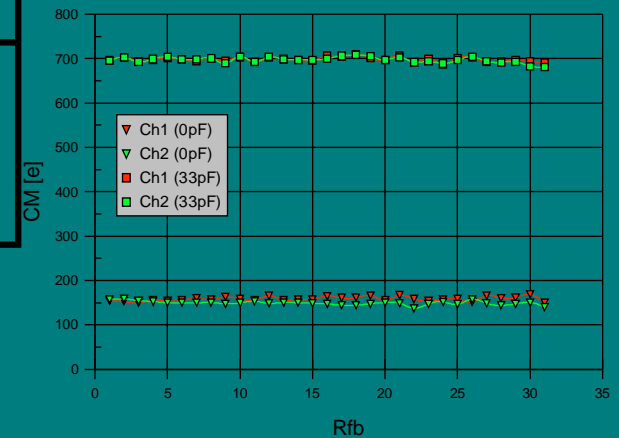
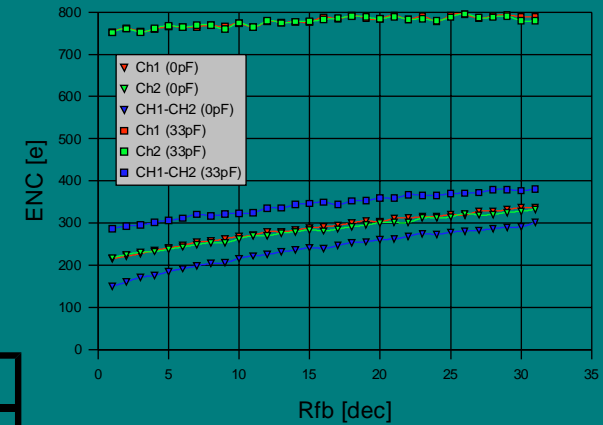
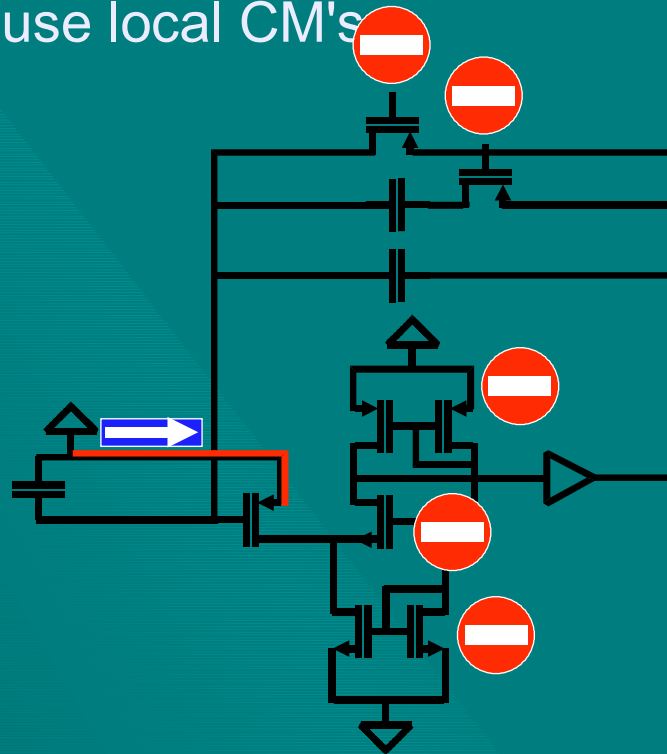
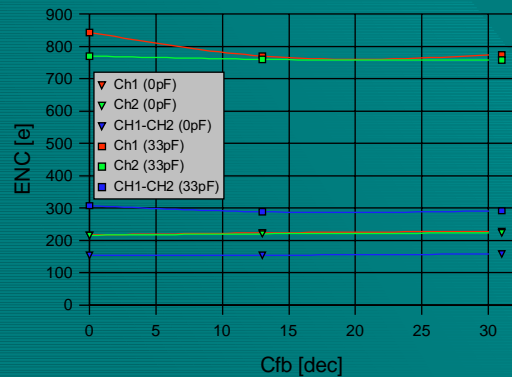
● $ENC = ENC(ChA-CHB) / \sqrt{2}$



		Offset	Slope
300K	sim.	120e	3.62e/pF
	meas.	143e	4.54e/pF
77K	sim.	60e	1.73e/pF
	meas.	121e	3.99e/pF

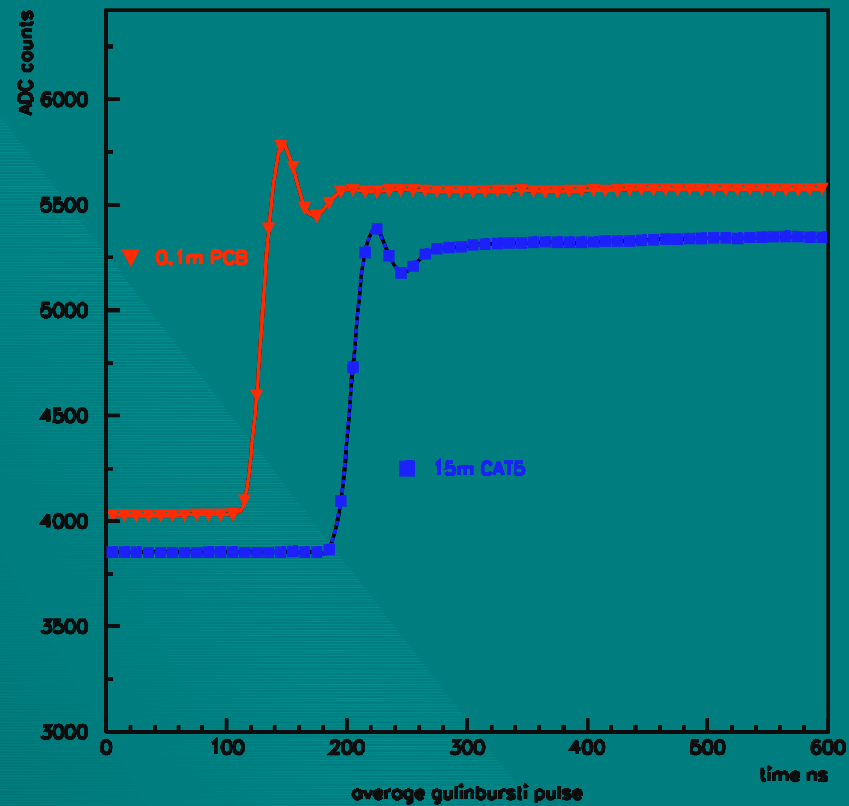
Search for a Correlated Noise Source

- 3 Sensitive Nodes
- R_{fb} -Gate Voltage
- C_{fb} -Switches
- Input FET Source Node
- 2 other Nodes use local CM's



Long Cables

- 15m CAT5 Cable
- 50Ω series Termination, 100Ω parallel Termination
- 1.2% Attenuation
- No Change in Rise-Time or Noise



Summary & Conclusions

- ✓ F-CSA104 works!
- ✓ Can drive 15m TP Cable
- ✓ works at 77K
- ✓ stable Adjustment of R_{fb} and Bias (at 300K and 77K)
- ✓ Linearity better than 14bit Equivalent
- Excess Noise at Room Temperature: 18% (30%)
- ✗ Noise improves by 18% (11%) instead of 50% at 77K
- ✗ huge Common Mode

Next Steps depend on.....

- Simulation Results at MPI
- Noise of Setup with new PCB
- Clues on the Correlated Noise Source